

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082431	02/22/2002	324	7.3	2858	N. Le

**APPLICANTS: Zhang Wei;

He

**CONTINUING DATA VERIFIED:

None on

** FOREIGN APPLICATIONS VERIFIED:

None on

PG-PUB	DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO	
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		SUN-P6557	
Verified and Acknowledged Examiners's initials		ah	
TITLE : Integrated electromigration length effect testing method and apparatus			
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner Amy He	
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Fig. Drawn
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
		PREPARED FOR ISSUE	
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